



FXN0206C Series

Rev.A

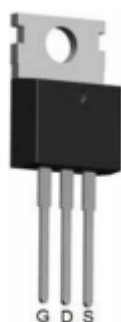
General Description

The FXN0206C uses advanced Silicon's MOSFET Technology, which provides high performance in on-state resistance, fast switching performance, and excellent quality.

These devices can also be utilized in industrial applications such as Low Power Drives SMPS, DC/DC converter, and general purpose applications.

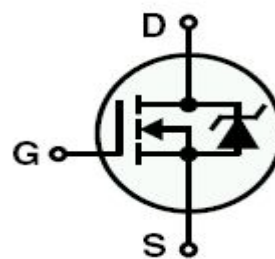
Features

- VDS = 65V
- ID = 190A @VGS = 10V
- Very low on-resistance
- RDS(ON) < 2.8mΩ @VGS = 10V
- 100% UIL Tested
- 100% Rg Tested
- 150 °C operating temperature



To-220 Top View

N-channel



Schematic Diagram

Absolute Maximum Ratings (T_J = 25 °C)

Characteristics	Symbol	Rating	Unit
Drain-Source Voltage	VDSS	65	V
Gate-Source Voltage	VGSS	±30	V
Continuous Drain Current (1)	ID	Tc=25°C(silicon limited)	190
		Tc=25°C(package limited)	145
		Tc=100°C(silicon limited)	118
Pulsed Drain Current (2)	IDM	750	A
Power Dissipation	PD	Tc=25°C	160
		Tc=100°C	116
Single Pulse Avalanche Energy (3)	EAS	850	mJ
Junction and Storage Temperature Range	TJ, Tstg	-55~175	°C

Thermal Characteristics

Characteristics	Symbol	Rating	Unit
Thermal Resistance, Junction-to-Ambient (1)	RθJA	62.5	°C/W
Thermal Resistance, Junction-to-Case	RθJC	0.85	



Electrical Characteristics (T_J = 25°C)

Characteristics	Symbol	Test Condition	Min	Typ	Max	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	I _D = 250μA, V _{GS} = 0V	65		-	V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	2		4	
Drain Cut-Off Current	I _{DSS}	V _{DS} = 60V, V _{GS} = 0V	-	-	1	μA
Gate Leakage Current	I _{GSS}	V _{GS} = ±30V, V _{DS} = 0V	-	-	±0.1	
Drain-Source ON Resistance	R _{DS(ON)}	V _{GS} = 10V, I _D = 30A	-	2.3	2.8	mΩ
Forward Transconductance	g _{fs}	V _{DS} = 30V, I _D = 40A	-	-	-	S
Dynamic Characteristics						
Total Gate Charge	Q _g	V _{DS} = 50V, I _D = 40A, V _{GS} = 10V	-	148		nC
Gate-Source Charge	Q _{gs}		-	19.6	-	
Gate-Drain Charge	Q _{gd}		-	52	-	
Input Capacitance	C _{iss}	V _{DS} = 25V, V _{GS} = 0V, f = 1.0MHz	-	5750	-	pF
Reverse Transfer Capacitance	C _{rss}		-	513	-	
Output Capacitance	C _{oss}		-	530	-	
Turn-On Delay Time	t _{d(on)}	V _{GS} = 10V, V _{DS} = 30V, I _D = 40A, R _G = 2.5Ω	-	26	-	ns
Rise Time	t _r		-	37	-	
Turn-Off Delay Time	t _{d(off)}		-	68	-	
Fall Time	t _f		-	34	-	
Gate Resistance	R _g	f = 1 MHz	-		-	Ω
Drain-Source Body Diode Characteristics						
Source-Drain Diode Forward Voltage	V _{SD}	I _S = 40A, V _{GS} = 0V	-	0.9	1.2	V
Body Diode Reverse Recovery Time	t _{rr}	I _F = 40A, di/dt = 100A/μs	-	38		ns
Body Diode Reverse Recovery Charge	Q _{rr}		-	32		nC

Note

1. Surface mounted FR-4 board by JEDEC (jesd51-7)
2. Pulse width limited by T_{Jmax}
3. EAS is tested at starting T_J = 25°C, L = 50mH, I_{AS} = 45A, V_{GS} = 10V VDD=50V



Typical Characteristics (T_J=25°C Noted)

Figure1. Output Characteristics

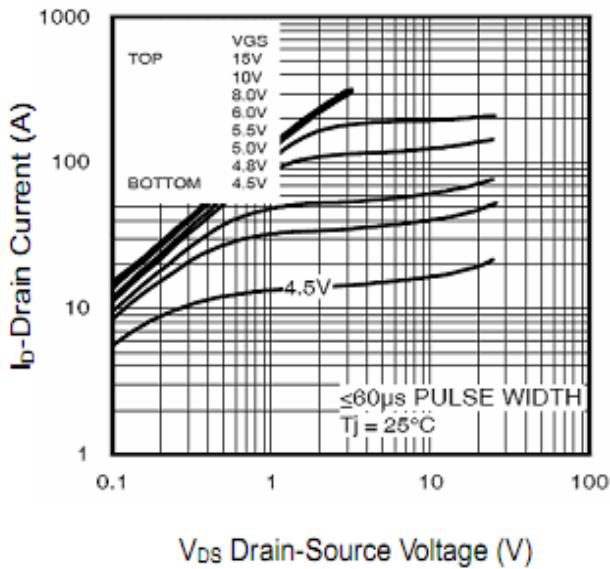


Figure2. Transfer Characteristics

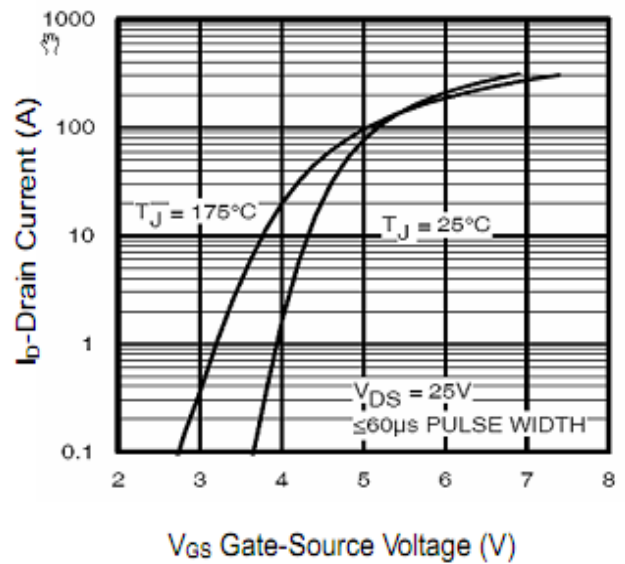


Figure3. BVDSS vs Junction Temperature

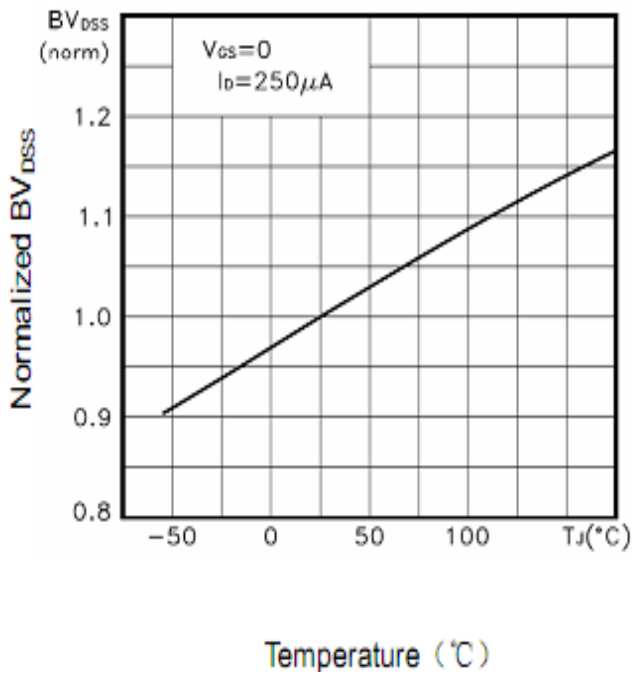


Figure4. I_D vs Junction Temperature

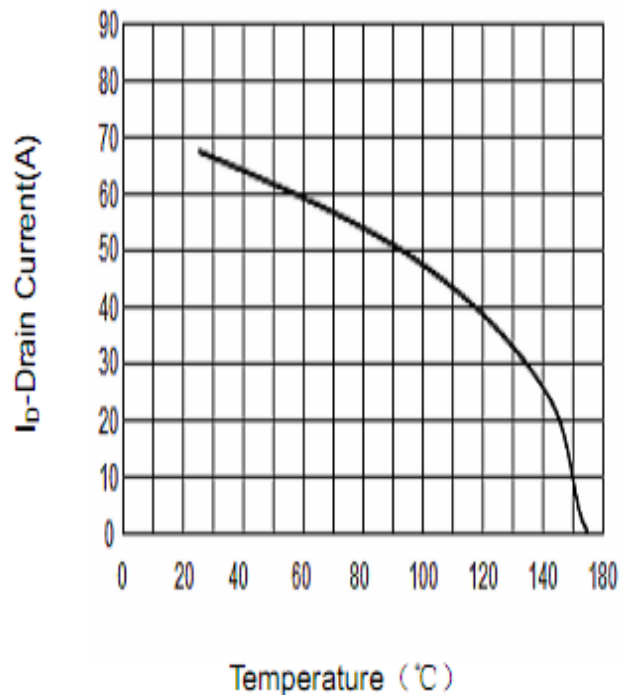




Figure5. VGS(th) vs Junction Temperature

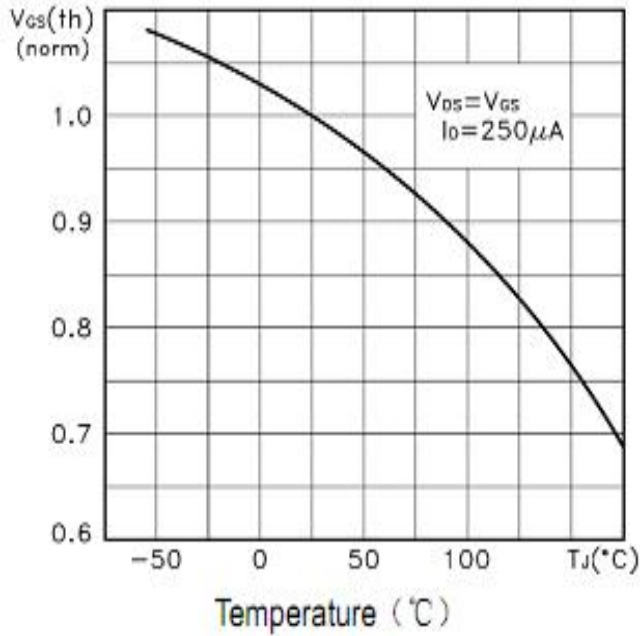


Figure6. R_{ds(on)} Vs Junction Temperature

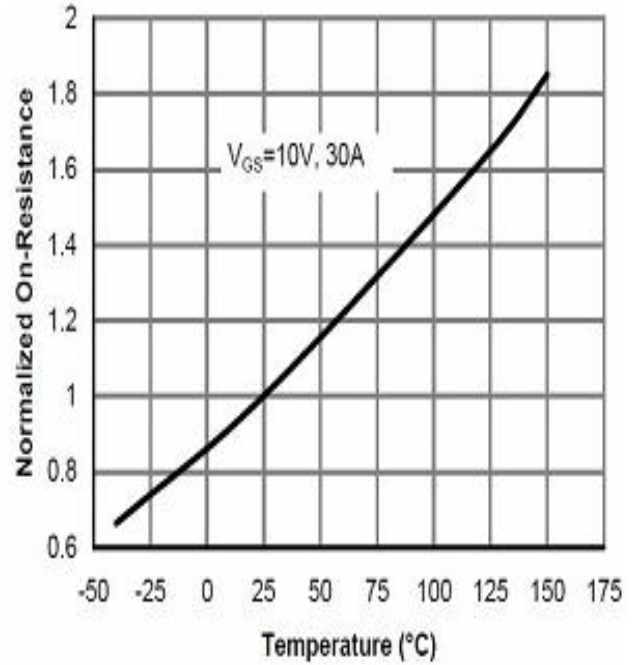


Figure7. Gate Charge

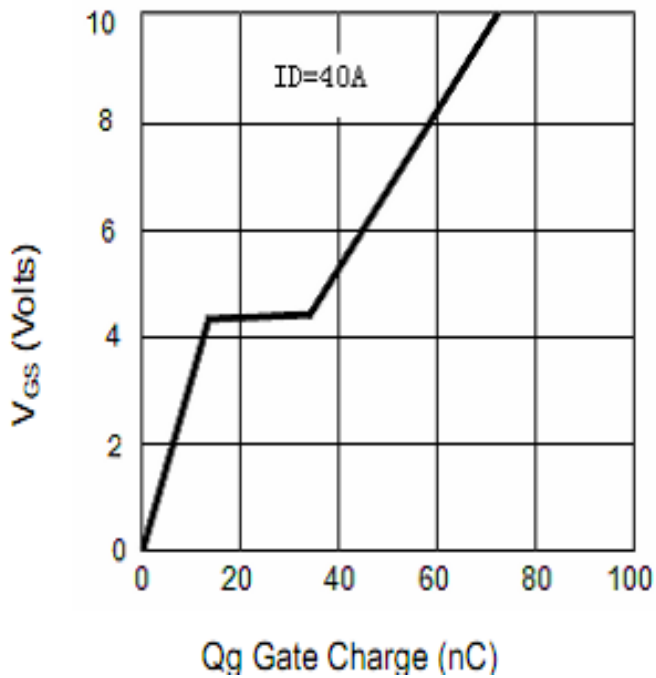


Figure8. Capacitance vs V_{ds}

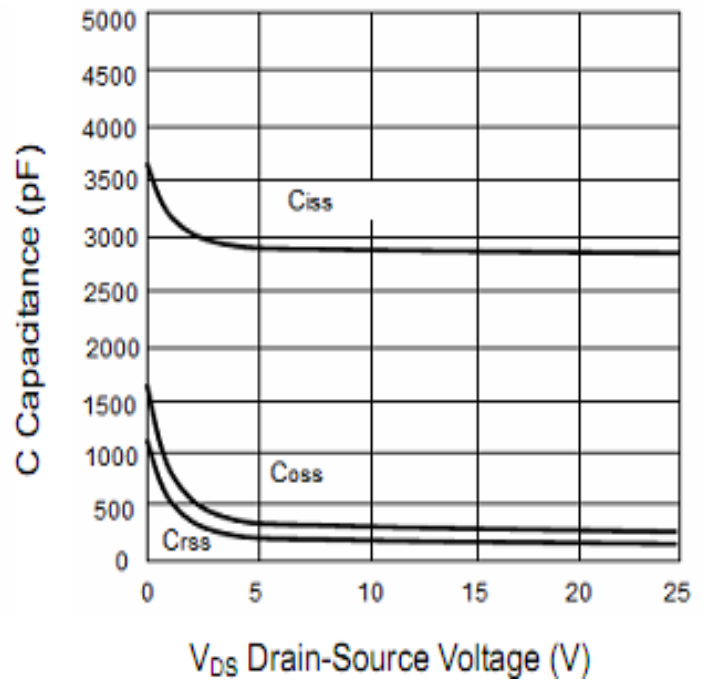




Figure9. Source- Drain Diode Forward

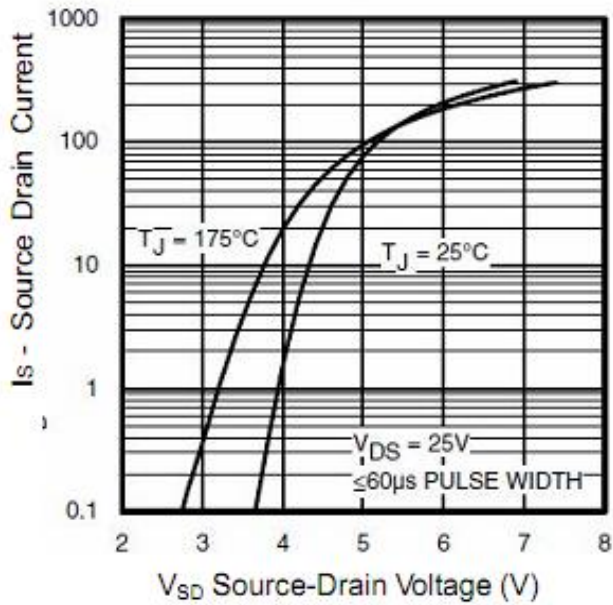


Figure10. Safe Operation Area

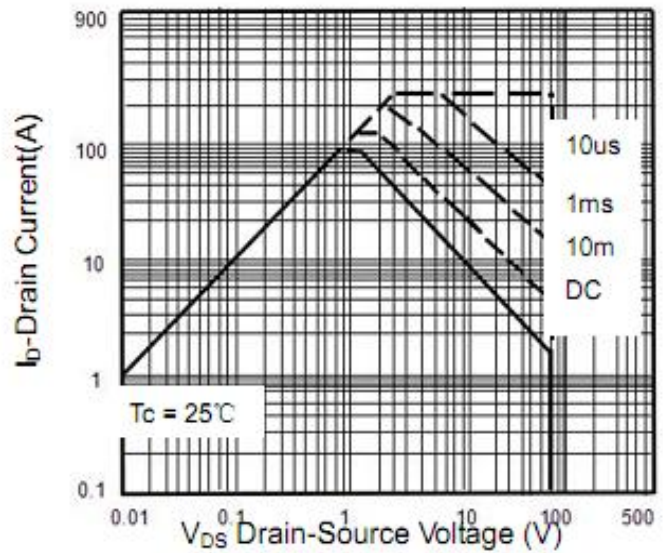
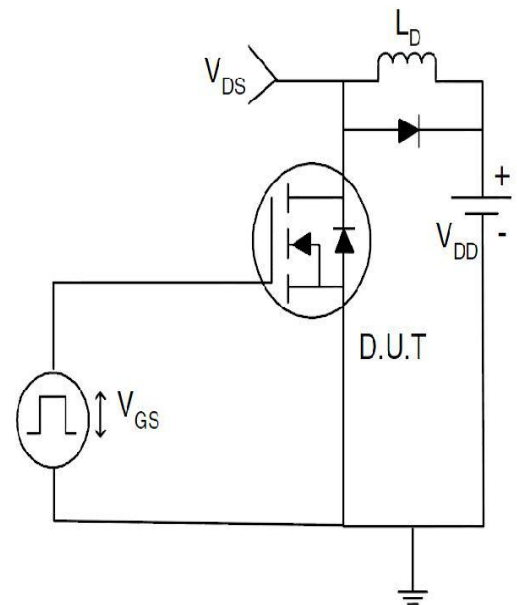
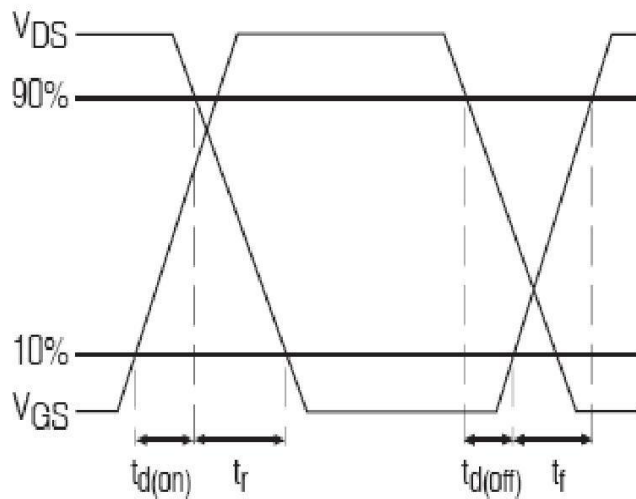
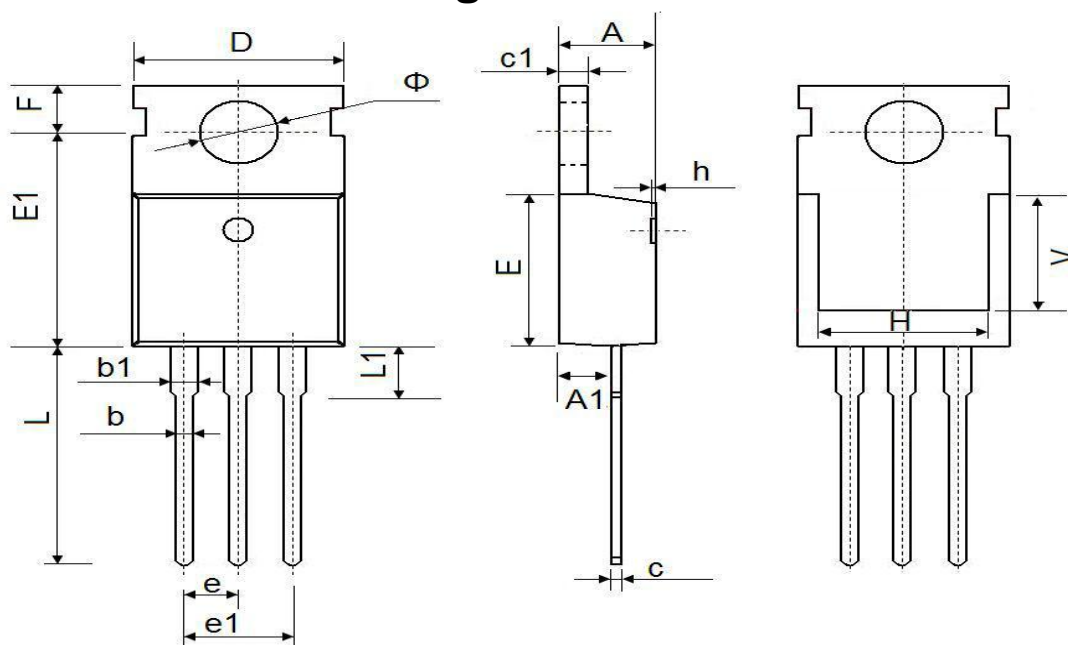


Figure 10.Switch Time Test Circuit:





TO-220 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max
A	4.300	4.700	0.169	0.185
A1	2.200	2.600	0.087	0.102
b	0.700	0.950	0.028	0.037
b1	1.170	1.410	0.046	0.056
c	0.450	0.650	0.018	0.026
c1	1.200	1.400	0.047	0.055
D	9.600	10.400	0.378	0.409
E	8.8200	9.750	0.348	0.384
E1	12.650	12.950	0.498	0.510
e	2.540 TYP.		0.100TYP.	
e1	4.980	5.180	0.196	0.204
F	2.650	2.950	0.104	0.116
H	7.900	8.100	0.311	0.319
h	0.000	0.300	0.000	0.012
L	12.750	14.300	0.502	0.563
L1	2.850	3.950	0.112	0.156
V	7.200 REF.		0.295 REF.	
Φ	3.400	4.000	0.134	0.157